

FDB5690-VB Datasheet N-Channel 60 V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A) ^{a, e}	Q _g (Max)			
60	$0.032 \text{ at V}_{GS} = 10 \text{ V}$	50	66 nC			
	0.035 at V _{GS} = 4.5 V	40	00 110			

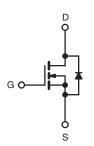
FEATURES

- Halogen-free According to IEC 61249-2-21 Definition
- Surface Mount
- Available in Tape and Reel
- Dynamic dV/dt Rating
- Logic-Level Gate Drive
- Fast Switching
- Compliant to RoHS Directive 2002/95/EC









N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage	V_{DS}	60	V			
Gate-Source Voltage			V_{GS}	± 10	v	
Continuous Drain Current ^f	V _{GS} at 10 V	$T_{\rm C} = 25 ^{\circ}{\rm C}$ $T_{\rm C} = 100 ^{\circ}{\rm C}$	1	50	А	
Continuous Drain Current	V _{GS} at 10 V	T _C = 100 °C	ID	36		
Pulsed Drain Current ^a			I _{DM}	200		
Linear Derating Factor				1.0	W/°C	
Linear Derating Factor (PCB Mount)e		0.025	VV/ C			
Single Pulse Avalanche Energy ^b	E _{AS}	400	mJ			
Maximum Power Dissipation	T _C = 25 °C		0	150	W	
Maximum Power Dissipation (PCB Mount)e	T _A = 25 °C		P_{D}	3.7		
Peak Diode Recovery dV/dtc	dV/dt	4.5	V/ns			
Operating Junction and Storage Temperature Rang	T _J , T _{stg}	- 55 to + 175	°C			
Soldering Recommendations (Peak Temperature) ^d for 10 s				300 ^d]	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD} = 25$ V, starting $T_J = 25$ °C, L = 179 μ H, $R_g = 25$ Ω , $I_{AS} = 51$ A (see fig. 12). c. $I_{SD} \le 51$ A, $I_{AS} = 51$

- d. 1.6 mm from case.
- e. When mounted on 1" square PCB (FR-4 or G-10 material).
- f. Current limited by the package, (die current = 51 A).



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-	62			
Maximum Junction-to-Ambient (PCB Mount) ^a	R _{thJA}	R _{thJA} - 40		°C/W		
Maximum Junction-to-Case (Drain)	R _{thJC}	-	1.0			

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

SPECIFICATIONS ($T_J = 25 ^{\circ}\text{C}$, unless otherwisk ARAMETER SYMBOL		TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static		<u> </u>		<u> </u>	<u>L</u>		
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0$, $I_D = 250 \mu A$		60	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference to 25 °C, I _D = 1 mA		-	0.070	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA		1.0	-	3.0	V
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 10 V		-	-	± 100	nA
Zero Onto Vellano Burio O con d	I _{DSS}	V _{DS} = 60 V, V _{GS} = 0 V		-	-	25	μΑ
Zero Gate Voltage Drain Current		V _{DS} = 48 V	V _{DS} = 48 V, V _{GS} = 0 V, T _J = 150 °C		-	250	
5 . 6 . 6	_	V _{GS} = 10 V	I _D = 21 A ^b	-	0.032	-	Ω
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 4.5 V	I _D = 15 A ^b	-	0.035	-	
Forward Transconductance	9 _{fs}	V _{DS} = 25 V, I _D = 21A ^b		23	-	-	S
Dynamic						l	
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ $f = 1.0 \text{ MHz}, \text{ see fig. 5}$		-	3000	-	pF
Output Capacitance	C _{oss}			-	1000	-	
Reverse Transfer Capacitance	C _{rss}			-	200	-	
Total Gate Charge	Qg			-	60	-	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 5.0 V	$I_D = 51 \text{ A}, V_{DS} = 48 \text{ V},$ see fig. 6 and 13^b	-	10	-	
Gate-Drain Charge	Q _{gd}	see lig. 6 and 13"		-	40	-	
Turn-On Delay Time	t _{d(on)}			-	17	-	
Rise Time	t _r	$V_{DD} = 30 \text{ V}, I_D = 51 \text{ A},$		-	230	-	- ns
Turn-Off Delay Time	t _{d(off)}	$R_{g} = 4.6 \Omega, R_{D} = 0.56 \Omega, \text{ see fig. } 10^{b}$		-	42	-	
Fall Time	t _f	1		-	110	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from		-	4.5	-	الم
Internal Source Inductance	L _S	package and center of die contact		-	7.5	-	- nH
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the		-	-	50°	- A
Pulsed Diode Forward Current ^a	I _{SM}	integral reverse p - n junction diode		-	-	200	
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 51 A, V _{GS} = 0 V ^b		-	-	2.5	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 51 A, dl/dt = 100 A/μs ^b		-	130	180	ns
Body Diode Reverse Recovery Charge	Q_{rr}			-	0.84	1.3	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-		on is dor	minated by L _S and L _D)		

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
 b. Pulse width ≤ 300 μs; duty cycle ≤ 2 %.
 c. Current limited by the package, (Die Current = 51 A).



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

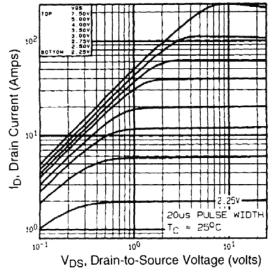


Fig. 1 - Typical Output Characteristics, $T_C = 25$ °C

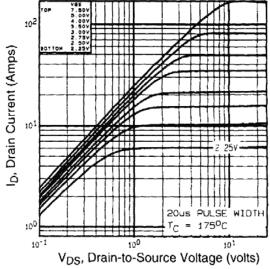


Fig. 2 - Typical Output Characteristics, $T_C = 150 \, ^{\circ}\text{C}$

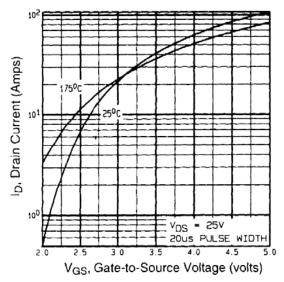


Fig. 3 - Typical Transfer Characteristics

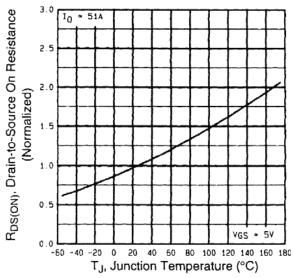


Fig. 4 - Normalized On-Resistance vs. Temperature



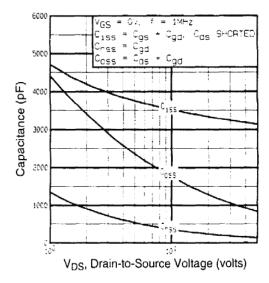


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

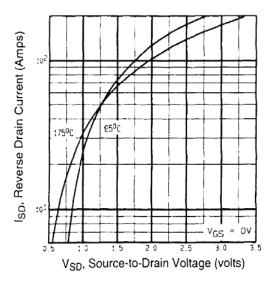


Fig. 7 - Typical Source-Drain Diode Forward Voltage

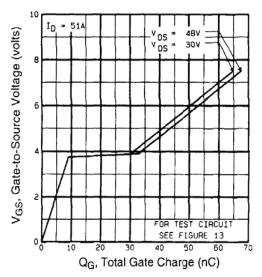


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

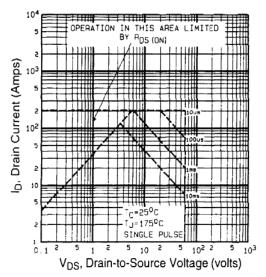


Fig. 8 - Maximum Safe Operating Area



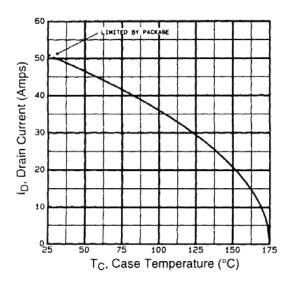


Fig. 9 - Maximum Drain Current vs. Case Temperature

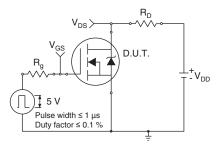


Fig. 10a - Switching Time Test Circuit

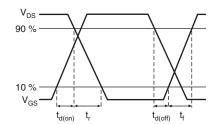


Fig. 10b - Switching Time Waveforms

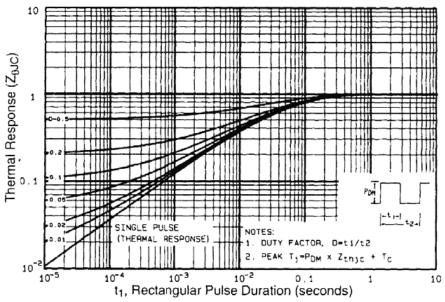
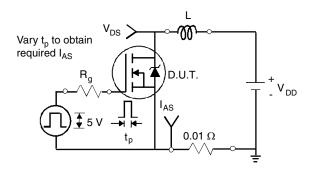


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

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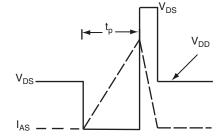


Fig. 12a - Unclamped Inductive Test Circuit

Fig. 12b - Unclamped Inductive Waveforms

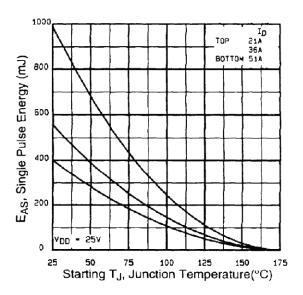


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

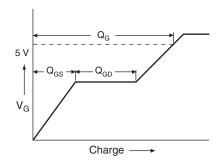


Fig. 13a - Basic Gate Charge Waveform

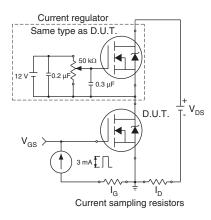
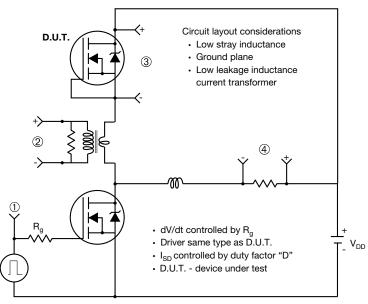


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



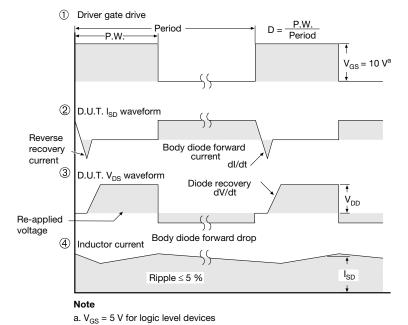
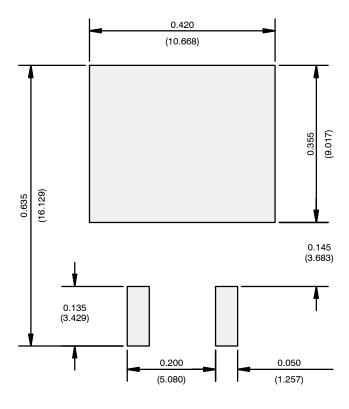


Fig. 14 - For N-Channel



RECOMMENDED MINIMUM PADS FOR D²PAK: 3-Lead



Recommended Minimum Pads Dimensions in Inches/(mm)



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